Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/091,769	SUNG WON LEE	
Examiner	Art Unit	
Binh Q. Nauven	2664	

	SEAR	CHED	
Class	Subclass	Date	Examiner
370	336	11/17/2005	BQN
370	342	11/17/2005	BQN
370	465	11/17/2005	BQN
370	392	11/17/2005	BQN
455	466	11/17/2005	BQN
370	331	11/17/2005	BQN
370	389	11/17/2005	BQN

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			L

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-GPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB), see more on search history.	11/17/2005	BQN
Consulted with SPE Wellington Chin	11/17/2005	BQN